


<b>Search Notes</b>  	<b>Application/Control No.</b>  10812051	<b>Applicant(s)/Patent Under Reexamination</b>  MIWA ET AL.
	<b>Examiner</b>  Hung, Yubin	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	164, 167, 173, 199, 274	9/28/08	YH
345	593	9/28/08	YH
358	520	9/28/08	YH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST T (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)	9/28/08	YH
IEEE Xplore	10/18/07	YH
Inventor/assignee search (EAST, eDAN)	9/28/08	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/YUBIN HUNG/ Primary Examiner.Art Unit 2624
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